



40V COMPLEMENTARY ENHANCEMENT MODE MOSFET H-BRIDGE

Product Summary

Device	V _{(BR)DSS}	R _{DS(ON)} max	I _D max T _A = +25°C
N-Channel	Channel 40V 45mΩ @ V _{GS} = 10V		4.5A
N-Channel	400	$58m\Omega$ @ V_{GS} = $4.5V$	4A
P-Channel	Channel -40V 65mΩ @ V _{GS} = -10V		-3.7A
P-Channel	-4 0V	100mΩ @ V _{GS} = -4.5V	-2.9A

Description

This new generation complementary MOSFET H-Bridge features low on-resistance achievable with low gate drive.

Applications

- DC Motor Control
- DC-AC Inverters

Features

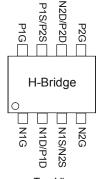
- 2 x N + 2 x P channels in a SOIC package
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

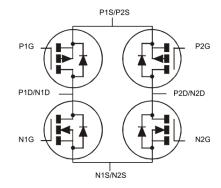
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
 UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe.
 Solderable per MIL-STD-202, Method 208 63
- Weight: 0.074 grams (approximate)







Top View Pin Configuration



Internal Schematic

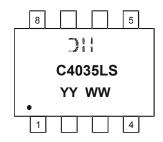
Ordering Information (Note 4)

Part Number	Compliance	Case	Packaging
DMHC4035LSD-13	Standard	SO-8	2500/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information



H = Manufacturer's Marking C4035LS = Product Type Marking Code YYWW = Date Code Marking YY = Year (ex: 13 = 2013) WW = Week (01 - 53)



Thermal Characteristics ($@T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic	Symbol	Value	Units		
Total Power Dissipation (Note 5)	P_{D}	1.5	W		
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	Б	85		
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{ heta JA}$	53	°C/W	
Thermal Resistance, Junction to Case		$R_{ heta JC}$	15		
Operating and Storage Temperature Range		T _{J,} T _{STG}	-55 to +150	°C	

Maximum Ratings N-CHANNEL (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units		
Drain-Source Voltage			V_{DSS}	40	V
Gate-Source Voltage			V _{GSS}	±20	V
Continuous Drain Courset (Nato 5) // - 40/	Steady State	T _A = +25°C T _A = +70°C	I _D	4.5 3.5	A
Continuous Drain Current (Note 5) V _{GS} = 10V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	5.8 4.5	А
Continuous Drain Correct (Note 5) // - 45)	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	4 3.1	А
Continuous Drain Current (Note 5) V _{GS} = 4.5V		$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	5.1 4	А
Maximum Continuous Body Diode Forward Curren	t (Note 5)	I _S	1.5	Α	
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	25	A

Maximum Ratings P-CHANNEL (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V_{DSS}	-40	V
Gate-Source Voltage			V_{GSS}	±20	V
		$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	-3.7 -2.9	Α
Continuous Drain Current (Note 5) V _{GS} = -10V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	-4.8 -3.8	Α
		T _A = +25°C T _A = +70°C	I _D	-2.9 -2.3	А
Continuous Drain Current (Note 5) V _{GS} = -4.5V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	-3.9 -3.0	Α
Maximum Continuous Body Diode Forward Current	I _S	-1.5	Α		
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	-15	А

Note: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.



Electrical Characteristics N-CHANNEL (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)				•		
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μA	V _{DS} = 40V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 6)				•		
Gate Threshold Voltage	V _{GS(th)}	1		3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	0	_	26	45	mΩ	$V_{GS} = 10V, I_D = 3.9A$
Static Dialii-Source Oil-Resistance	R _{DS} (ON)	_	35	58	11122	V _{GS} = 4.5V, I _D = 3.5A
Diode Forward Voltage	V_{SD}	_	0.7	1	V	V _{GS} = 0V, I _S = 1.25A
DYNAMIC CHARACTERISTICS (Note 7)				•		
Input Capacitance	Ciss	_	574	_		V _{DS} = 20V, V _{GS} = 0V, f = 1MHz
Output Capacitance	Coss	_	87.8	_	pF	
Reverse Transfer Capacitance	C _{rss}	_	38.7	_		
Gate resistance	R_g	_	1.6	_	Ω	V_{DS} = 0V, V_{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = 4.5V)	Qg	_	5.9	_		
Total Gate Charge (V _{GS} = 10V)	Qg	_	12.5	_	nC	V _{DS} = 20V. I _D = 3.9A
Gate-Source Charge	Q_{gs}	_	1.7	_	IIC	V _{DS} = 20V, I _D = 3.9A
Gate-Drain Charge	Q_{gd}	_	2.2	_		
Turn-On Delay Time	t _{D(on)}	_	3.1	_		
Turn-On Rise Time	t _r		2.6	_		$V_{DD} = 20V, V_{GS} = 10V,$
Turn-Off Delay Time	t _{D(off)}	_	15	_	ns	$R_L = 20\Omega$, $R_G = 6\Omega$,
Turn-Off Fall Time	t _f	_	5.5	_		
Reverse Recovery Time	t _{rr}	_	6.5	_	ns	1 - 2 0 4 - 11/44 - 500 4 /
Reverse Recovery Charge	Q _{rr}		1.2	_	nC	I _F = 3.9A, di/dt = 500A/μs

Electrical Characteristics P-CHANNEL (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)			•	•		
Drain-Source Breakdown Voltage	BV _{DSS}	-40	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	-1	μA	V _{DS} = -40V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 6)			•	•		
Gate Threshold Voltage	V _{GS(th)}	-1	_	-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
Static Drain-Source On-Resistance	D	_	49	65	mΩ	V _{GS} = -10V, I _D = -4.2A
Static Dialii-Source Off-Resistance	R _{DS} (ON)	_	73	100	11122	$V_{GS} = -4.5V$, $I_D = -3.3A$
Diode Forward Voltage	V _{SD}	_	-0.7	-1.2	V	V _{GS} = 0V, I _S = -1A
DYNAMIC CHARACTERISTICS (Note 7)						
Input Capacitance	C _{iss}	_	587	_	pF	.,
Output Capacitance	Coss	_	88.1	_	pF	$V_{DS} = -20V, V_{GS} = 0V,$ - f = 1MHz
Reverse Transfer Capacitance	C _{rss}	_	40.2	_	pF	71 - 1101112
Gate resistance	Rg	_	12.3	_	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = -4.5V)	Qg	_	5.4	_	nC	
Total Gate Charge (V _{GS} = -10V)	Qg	_	11.1	_	nC	V _{DS} = -20V. I _D = -4.2A
Gate-Source Charge	Q _{gs}	_	1.5	_	nC	$V_{DS} = -20V, I_D = -4.2A$
Gate-Drain Charge	Q _{gd}	_	2	_	nC	
Turn-On Delay Time	t _{D(on)}	_	3.6	_	ns	
Turn-On Rise Time	t _r	_	2.9	_	ns	V _{DD} = -15V, V _{GS} = -10V,
Turn-Off Delay Time	t _{D(off)}	_	36.3	_	ns	$R_G = 6\Omega$, $I_D = -1A$
Turn-Off Fall Time	t _f	_	15.3	_	ns	
Reverse Recovery Time	t _{rr}	_	15.5	_	ns	1 - 4 0 4 - 500 4 /
Reverse Recovery Charge	Q _{rr}	_	16.9	_	nC	$I_F = -4.2A$, di/dt = 500A/ μ s

6. Short duration pulse test used to minimize self-heating effect. 7. Guaranteed by design. Not subject to product testing. Notes:



Typical Characteristics - N-CHANNEL

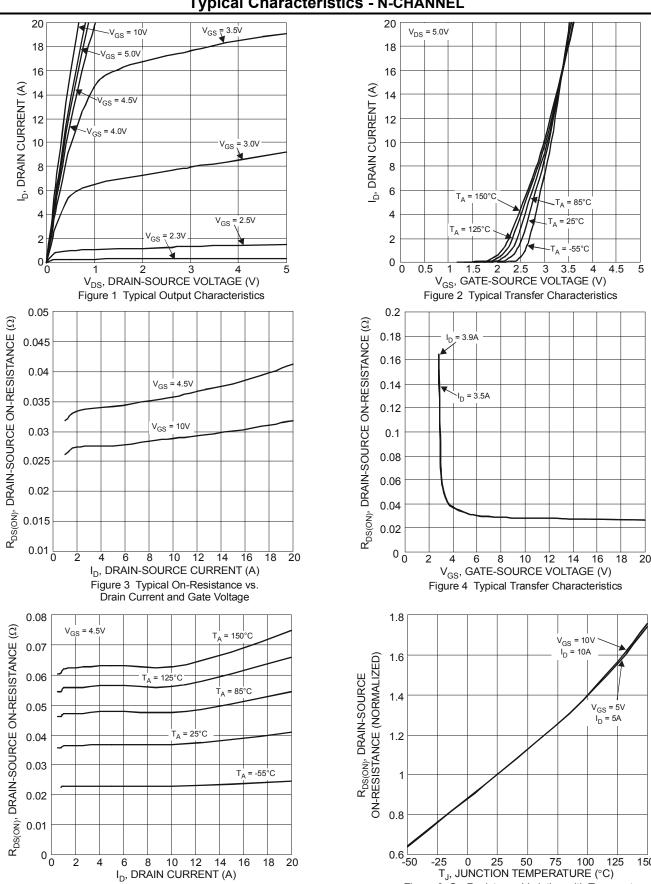
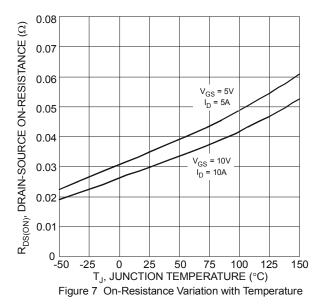
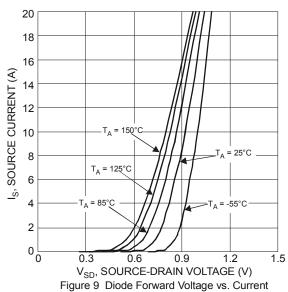


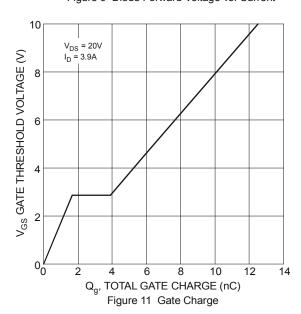
Figure 5 Typical On-Resistance vs. Drain Current and Temperature

Figure 6 On-Resistance Variation with Temperature









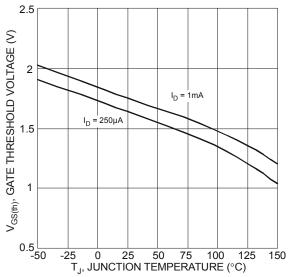
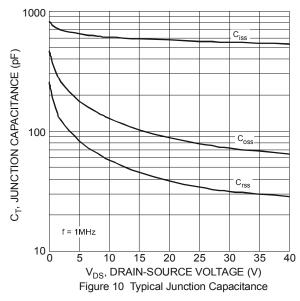
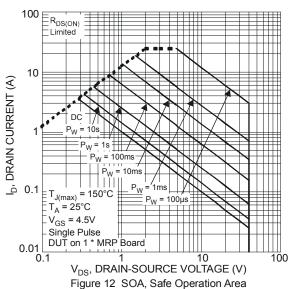


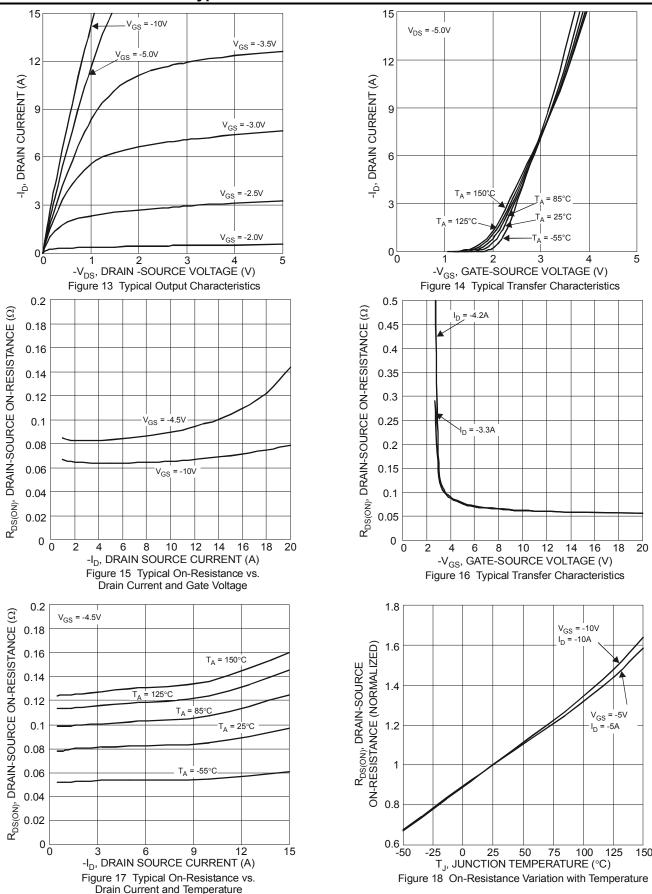
Figure 8 Gate Threshold Variation vs. Ambient Temperature







Typical Characteristics - P-CHANNEL





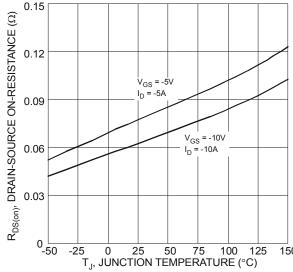
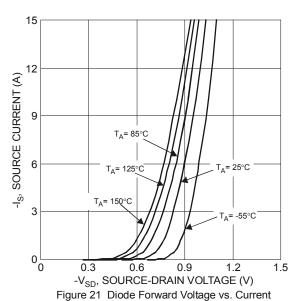
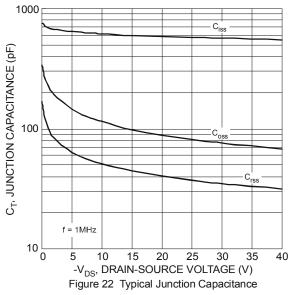


Figure 19 On-Resistance Variation with Temperature



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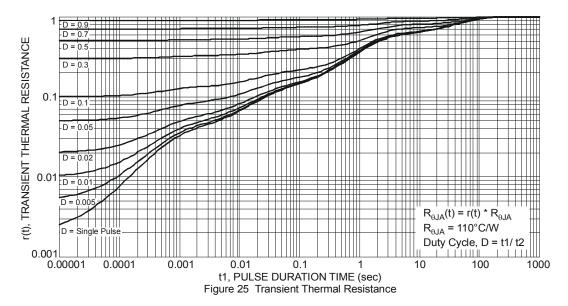
Figure 20 Gate Threshold Variation vs. Ambient Temperature



100
R_{DS(ON)}
Limited

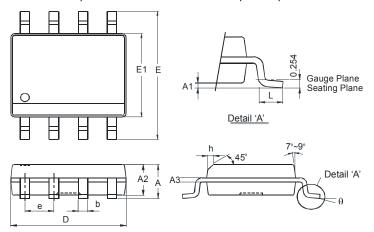
10
P_W = 10s
P_W = 10oms
P_W =





Package Outline Dimensions

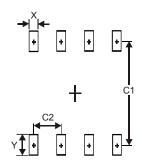
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8						
Dim	Min	Max				
Α	ı	1.75				
A1	0.10	0.20				
A2	1.30	1.50				
А3	0.15	0.25				
b	0.3	0.5				
D	4.85	4.95				
Е	5.90	6.10				
E1	3.85	3.95				
е	1.27	Тур				
h	ı	0.35				
L	0.62	0.82				
θ	0°	8°				
All Di	All Dimensions in mm					

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
X	0.60
Υ	1.55
C1	5.4
C2	1.27



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